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Supporting information for article:

***In situ* biaxial loading and multi-scale deformation measurements of nanostructured materials at the CoSAXS beamline at MAX IV Laboratory**

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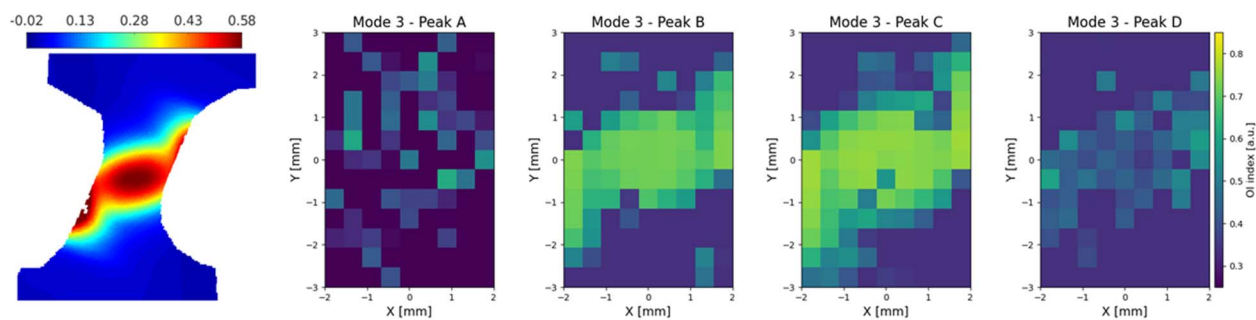


Figure S1 Full-field image of PC under deformation upon biaxial conditions (mode 3) and the corresponding spatial mapping of the OI index for from Peak A, B, C and D, respectively.